An Infineon Technologies Company

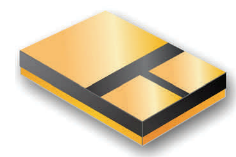
IRHNM57214SE

RADIATION HARDENED POWER MOSFET SURFACE MOUNT (SMD-0.2)

250V, N-CHANNEL
R5 TECHNOLOGY

Product Summary

Part Number	Radiation Level	RDS(on)	I_D
IRHNM57214SE	100 kRads(Si)	1.7Ω	2.4A



SMD-0.2
METAL LID

Description

IR HiRel R5 technology provides high performance power MOSFETs for space applications. These devices have been characterized for Single Event Effects (SEE) with useful performance up to an LET of 80 (MeV/(mg/cm^2)). The combination of low $R_{DS(on)}$ and low gate charge reduces the power losses in switching applications such as DC to DC converters and motor control. These devices retain all of the well established advantages of MOSFETs such as voltage control, fast switching, ease of paralleling and temperature stability of electrical parameters.

Features

- Single Event Effect (SEE) Hardened
- Low $R_{DS(on)}$
- Low Total Gate Charge
- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed
- Surface Mount
- Ceramic Package
- Light Weight
- ESD Rating: Class 1B per MIL-STD-750, Method 1020

Absolute Maximum Ratings — Pre-Irradiation

	Parameter		Units
I_D @ V_{GS} = 12V, T_C = 25°C	Continuous Drain Current	3.7	A
I_D @ V_{GS} = 12V, T_C = 100°C	Continuous Drain Current	2.4	
I_{DM}	Pulsed Drain Current ①	14.8	
P_D @T_C = 25°C	Maximum Power Dissipation	40	W
	Linear Derating Factor	0.32	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy ②	34	mJ
I_{AR}	Avalanche Current ①	3.7	A
E_{AR}	Repetitive Avalanche Energy ①	4.0	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.7	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 150	°C
	Pckg. Mounting Surface Temp.	300 (for 5s)	
	Weight	0.25 (Typical)	g

For Footnotes refer to the page 2.

Electrical Characteristics @ Tj = 25°C (Unless Otherwise Specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	250	—	—	V	V_{GS} = 0V, I_D = 1.0mA
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.27	—	V/°C	Reference to 25°C, I_D = 1.0mA
$R_{DS(on)}$	Static Drain-to-Source On-State Resistance	—	—	1.7	Ω	V_{GS} = 12V, I_D = 2.4A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.5	—	4.5	V	V_{DS} = V_{GS}, I_D = 1.0mA
$\Delta V_{GS(th)}/\Delta TJ$	Gate Threshold Voltage Coefficient	—	-9.1	—	mV/°C	
Gfs	Forward Transconductance	2.0	—	—	S	V_{DS} = 15V, I_D = 2.4A ④
I_{DSS}	Zero Gate Voltage Drain Current	—	—	10	µA	V_{DS} = 200V, V_{GS} = 0V
		—	—	25		V_{DS} = 200V, V_{GS} = 0V, T_J = 125°C
I_{GSS}	Gate-to-Source Leakage Forward	—	—	100	nA	V_{GS} = 20V
	Gate-to-Source Leakage Reverse	—	—	-100		V_{GS} = -20V
Q_G	Total Gate Charge	—	—	9.1	nC	I_D = 3.7A
Q_{GS}	Gate-to-Source Charge	—	—	2.9		V_{DS} = 125V
Q_{GD}	Gate-to-Drain ('Miller') Charge	—	—	4.3		V_{GS} = 12V
$t_{d(on)}$	Turn-On Delay Time	—	—	6.3	ns	V_{DD} = 125V
tr	Rise Time	—	—	6.3		I_D = 3.7A
$t_{d(off)}$	Turn-Off Delay Time	—	—	16.8		R_G = 7.5Ω
t_f	Fall Time	—	—	14		V_{GS} = 12V
Ls +L_D	Total Inductance	—	6.8	—	nH	Measured from the center of drain pad to center of source pad
C_{iss}	Input Capacitance	—	308	—	pF	V_{GS} = 0V
C_{oss}	Output Capacitance	—	51	—		V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	—	1.2	—		f = 1.0MHz
R_G	Gate Resistance	—	6.6	—	Ω	f = 1.0MHz,open drain

Source-Drain Diode Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I_S	Continuous Source Current (Body Diode)	—	—	3.7	A	
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	14.8		
V_{SD}	Diode Forward Voltage	—	—	1.0	V	T_J = 25°C, I_S = 3.7A, V_{GS} = 0V④
t_{rr}	Reverse Recovery Time	—	—	145	ns	T_J = 25°C, I_F = 3.7A, $V_{DD} \leq$ 25V
Q_{rr}	Reverse Recovery Charge	—	—	857	nC	di/dt = 100A/µs ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	—	3.12	°C/W

Footnotes:

① Repetitive Rating; Pulse width limited by maximum junction temperature.
② V_{DD} = 50V, starting T_J = 25°C, L =5.0mH, Peak I_L = 3.7A, V_{GS} = 12V
③ $I_{SD} \leq$ 3.7A, di/dt $\leq$ 1018A/µs, $V_{DD} \leq$ 250V, $T_J \leq$ 150°C
④ Pulse width $\leq$ 300 µs; Duty Cycle $\leq$ 2%
⑤ **Total Dose Irradiation with V_{GS} Bias.** 12 volt V_{GS} applied and V_{DS} = 0 during irradiation per MIL-STD-750, Method 1019, condition A.
⑥ **Total Dose Irradiation with V_{DS} Bias.** 200 volt V_{DS} applied and V_{GS} = 0 during irradiation per MIL-STD-750, Method 1019, condition A.

Radiation Characteristics

IR HiRel Radiation Hardened MOSFETs are tested to verify their radiation hardness capability. The hardness assurance program at IR Hirel is comprised of two radiation environments. Every manufacturing lot is tested for total ionizing dose (per notes 5 and 6) using the TO-3 package. Both pre- and post-irradiation performance are tested and specified using the same drive circuitry and test conditions in order to provide a direct comparison.

Table1. Electrical Characteristics @ Tj = 25°C, Post Total Dose Irradiation ⑤⑥

	Parameter	Up to 100 kRads (Si)[2]		Units	Test Conditions
		Min.	Max.		
BV_{DSS}	Drain-to-Source Breakdown Voltage	250	——	V	V_{GS} = 0V, I_D = 1.0mA
$V_{GS(th)}$	Gate Threshold Voltage	2.0	4.5	V	V_{DS} = V_{GS}, I_D = 1.0mA
I_{GSS}	Gate-to-Source Leakage Forward	——	100	nA	V_{GS} = 20V
I_{GSS}	Gate-to-Source Leakage Reverse	——	-100	nA	V_{GS} = -20V
I_{DSS}	Zero Gate Voltage Drain Current	——	10	µA	V_{DS} = 200V, V_{GS} = 0V
$R_{DS(on)}$	Static Drain-to-Source ④ On-State Resistance (TO-3)	——	1.7	Ω	V_{GS} = 12V, I_D = 2.4A
$R_{DS(on)}$	Static Drain-to-Source ④ On-State Resistance (SMD-0.2)	——	1.7	Ω	V_{GS} = 12V, I_D = 2.4A
V_{SD}	Diode Forward Voltage ④	——	1.0	V	V_{GS} = 0V, I_D = 3.7A

IR HiRel radiation hardened MOSFETs have been characterized in heavy ion environment for Single Event Effects (SEE). Single Event Effects characterization is illustrated in Fig. a and Table 2.

Table 2. Typical Single Event Effect Safe Operating Area

Ion	LET (MeV/(mg/cm^2))	Energy (MeV)	Range (µm)	V_{DS} (V)				
				@VGS=0V	@VGS=-5V	@VGS=-10V	@VGS=-15V	@VGS=-20V
Br	36.7	309	39.5	250	250	250	250	250
I	59.8	341	32.5	250	250	250	250	240
Au	82.3	350	28.4	250	250	225	175	50

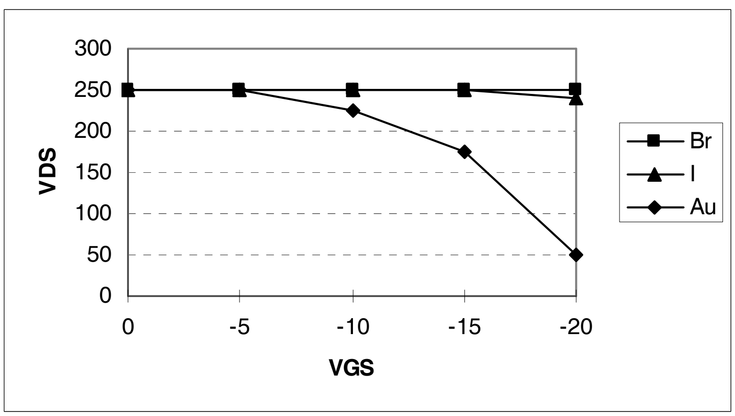


Fig a. Typical Single Event Effect, Safe Operating Area

For Footnotes, refer to the page 2.

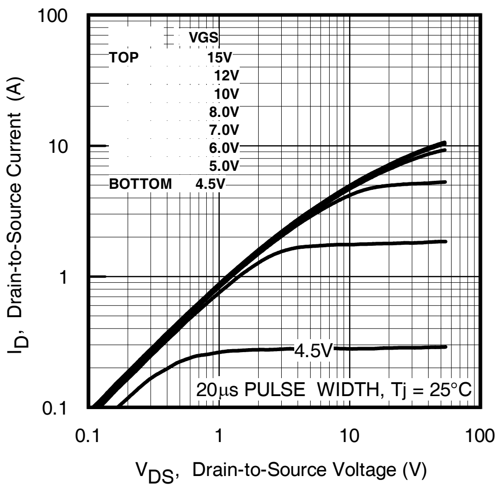


Fig 1. Typical Output Characteristics

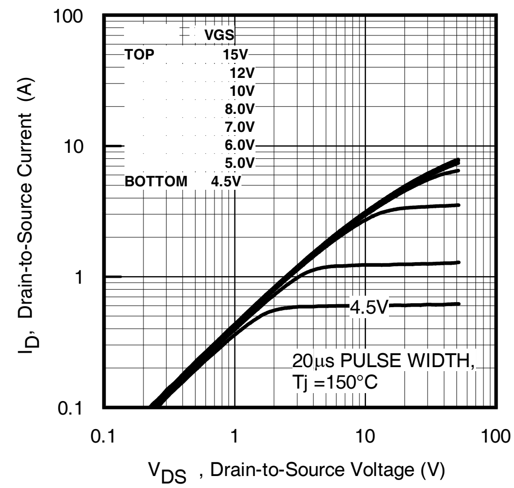


Fig 2. Typical Output Characteristics

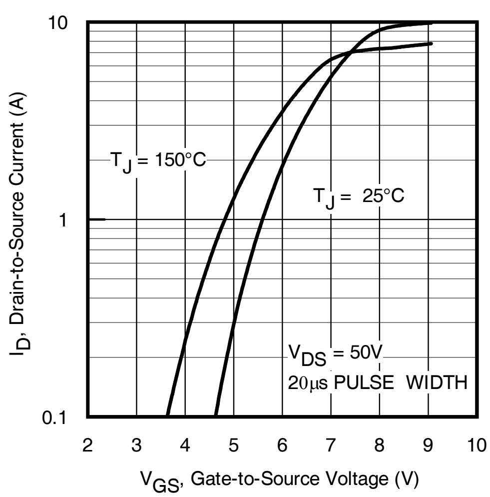


Fig 3. Typical Transfer Characteristics

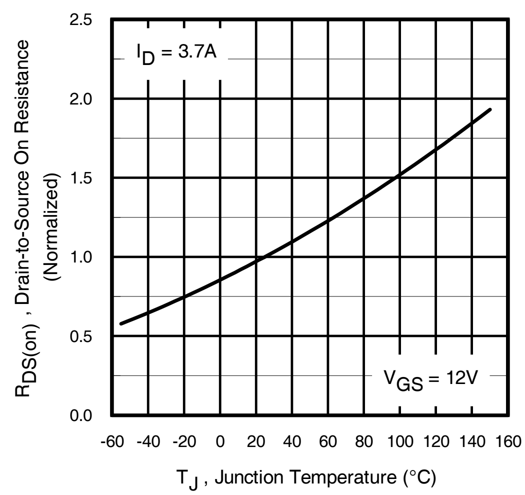


Fig 4. Normalized On-Resistance Vs. Temperature

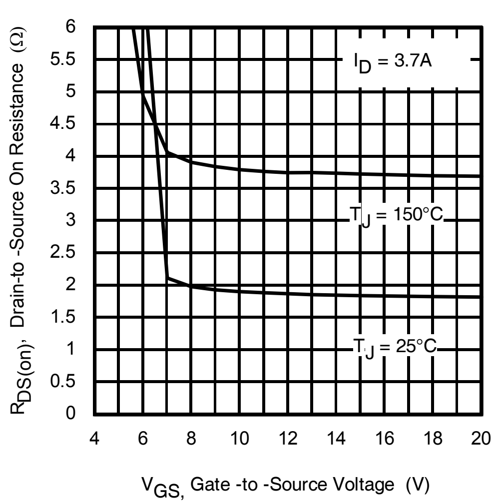


Fig 5. Typical On-Resistance Vs Gate Voltage

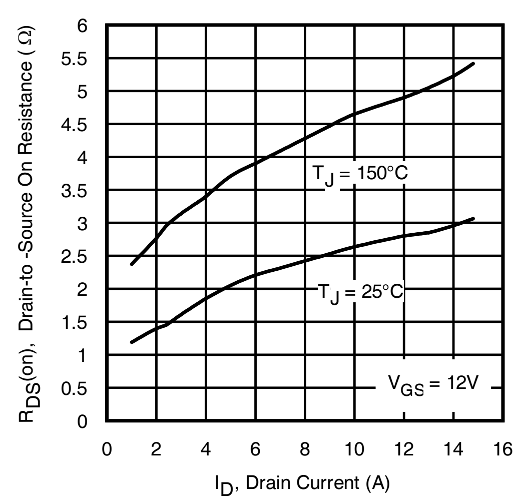


Fig 6. Typical On-Resistance Vs Drain Current

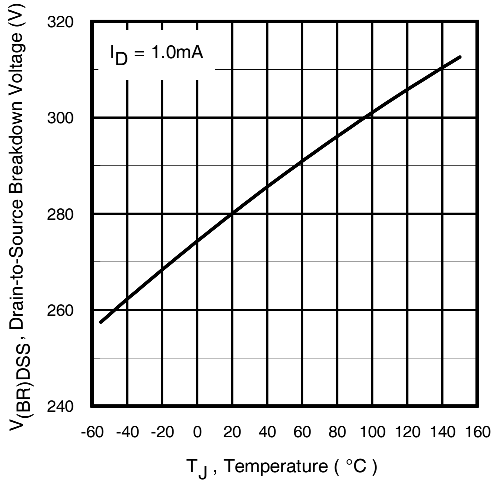


Fig 7. Typical Drain-to-Source Breakdown Voltage Vs Temperature

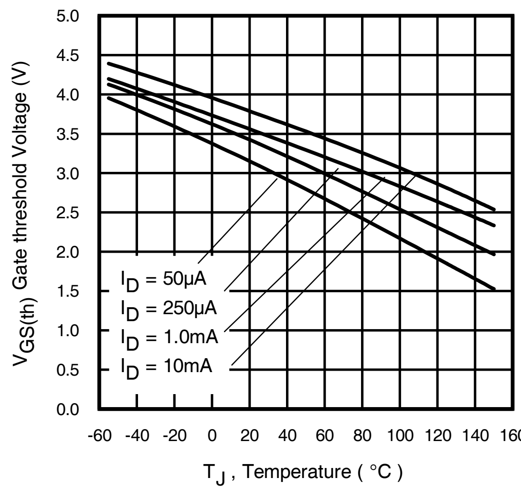


Fig 8. Typical Threshold Voltage Vs Temperature

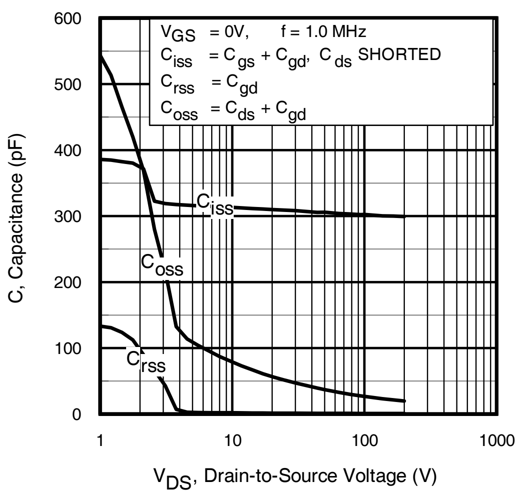


Fig 9. Typical Capacitance Vs. Drain-to-Source Voltage

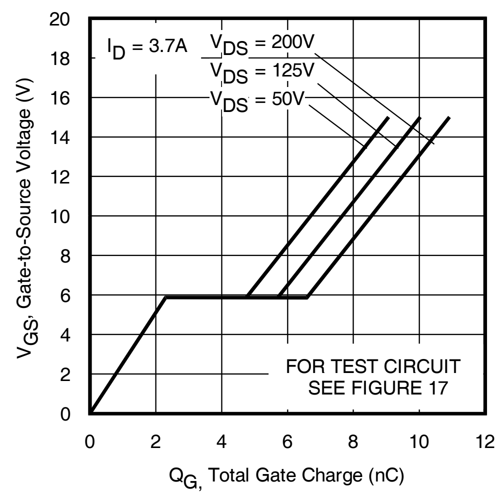


Fig 10. Typical Gate Charge Vs. Gate-to-Source Voltage

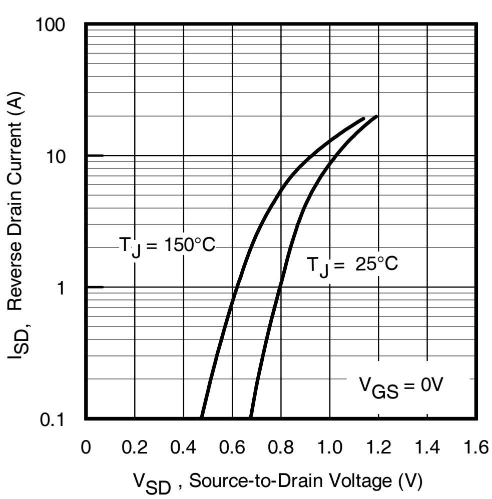


Fig 11. Typical Source-Drain Diode Forward Voltage

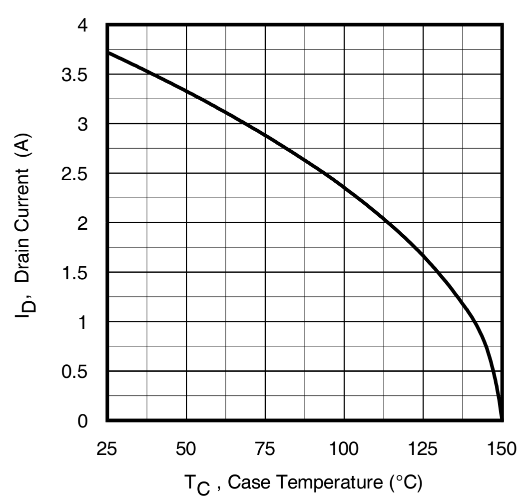


Fig 12. Maximum Drain Current Vs. Case Temperature

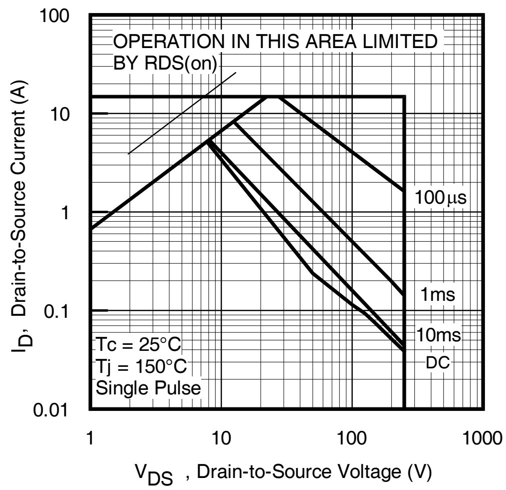


Fig 13. Maximum Safe Operating Area

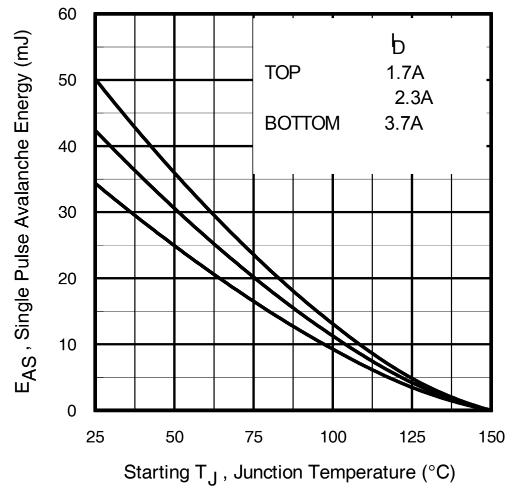


Fig 14. Maximum Avalanche Energy Vs. Drain Current

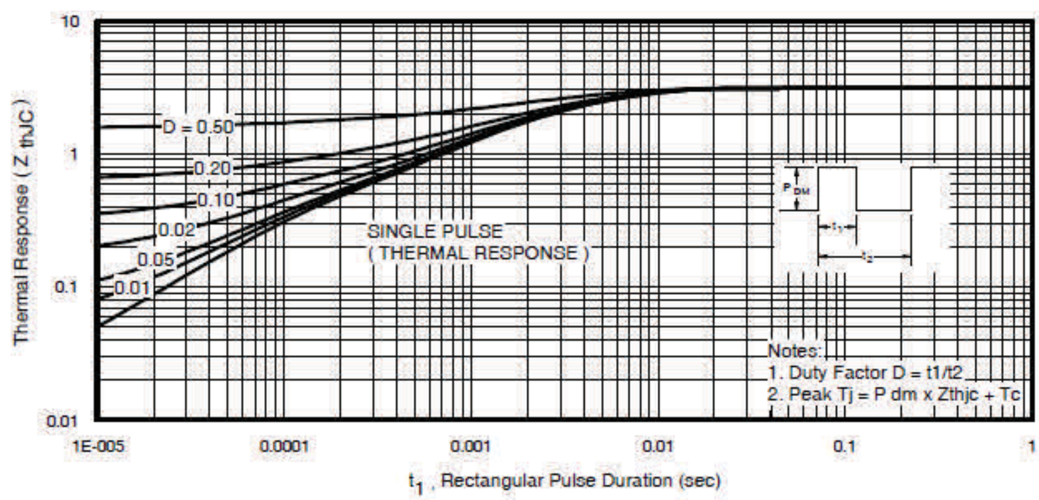


Fig 15. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

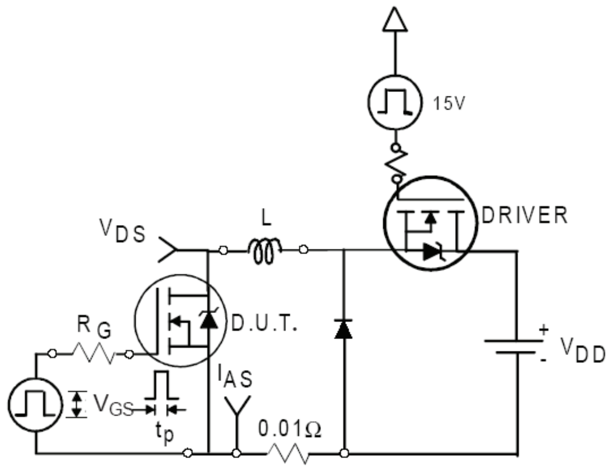


Fig 16a. Unclamped Inductive Test Circuit

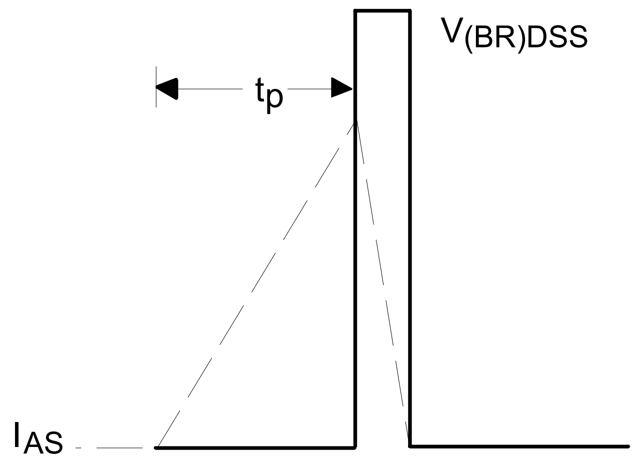


Fig 16b. Unclamped Inductive Waveforms

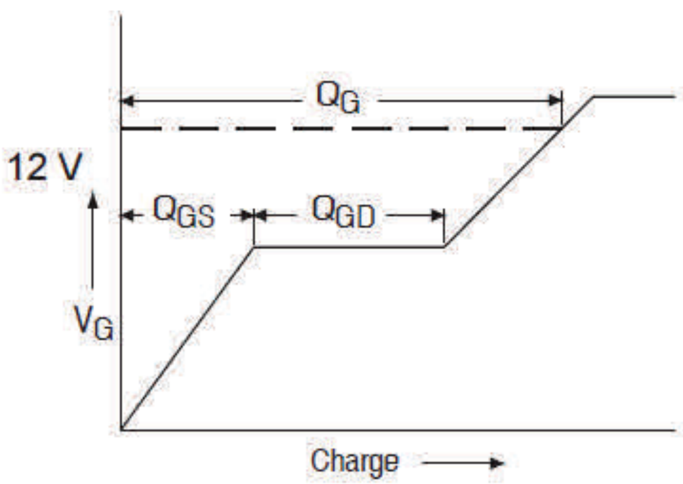


Fig 17a. Basic Gate Charge Waveform

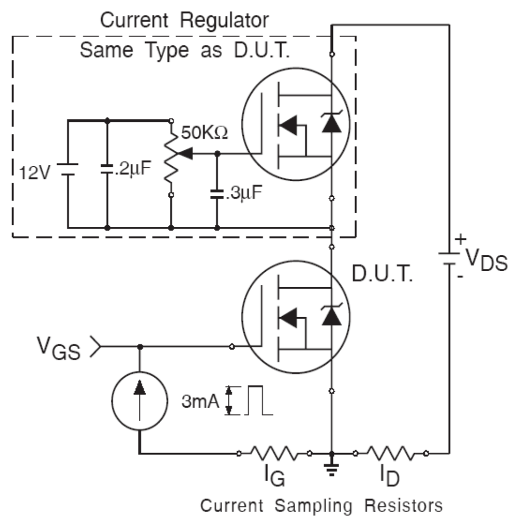


Fig 17b. Gate Charge Test Circuit

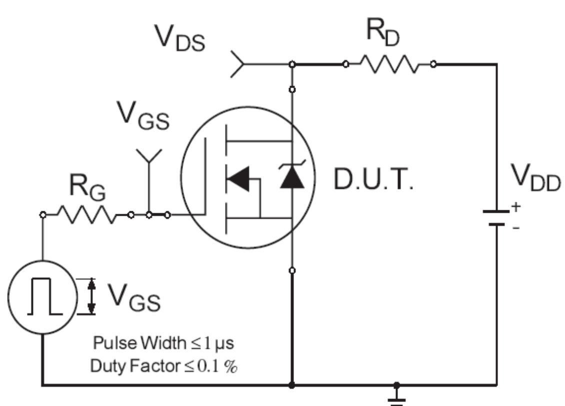


Fig 18a. Switching Time Test Circuit

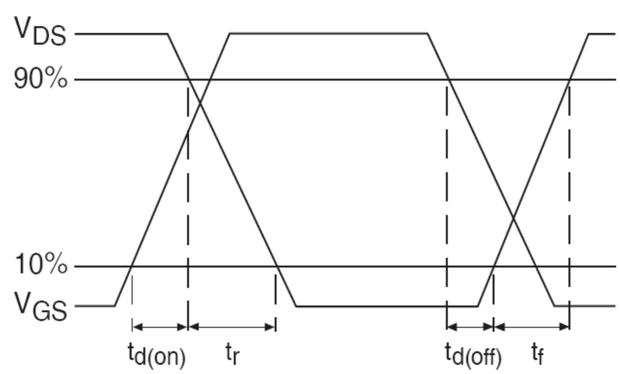
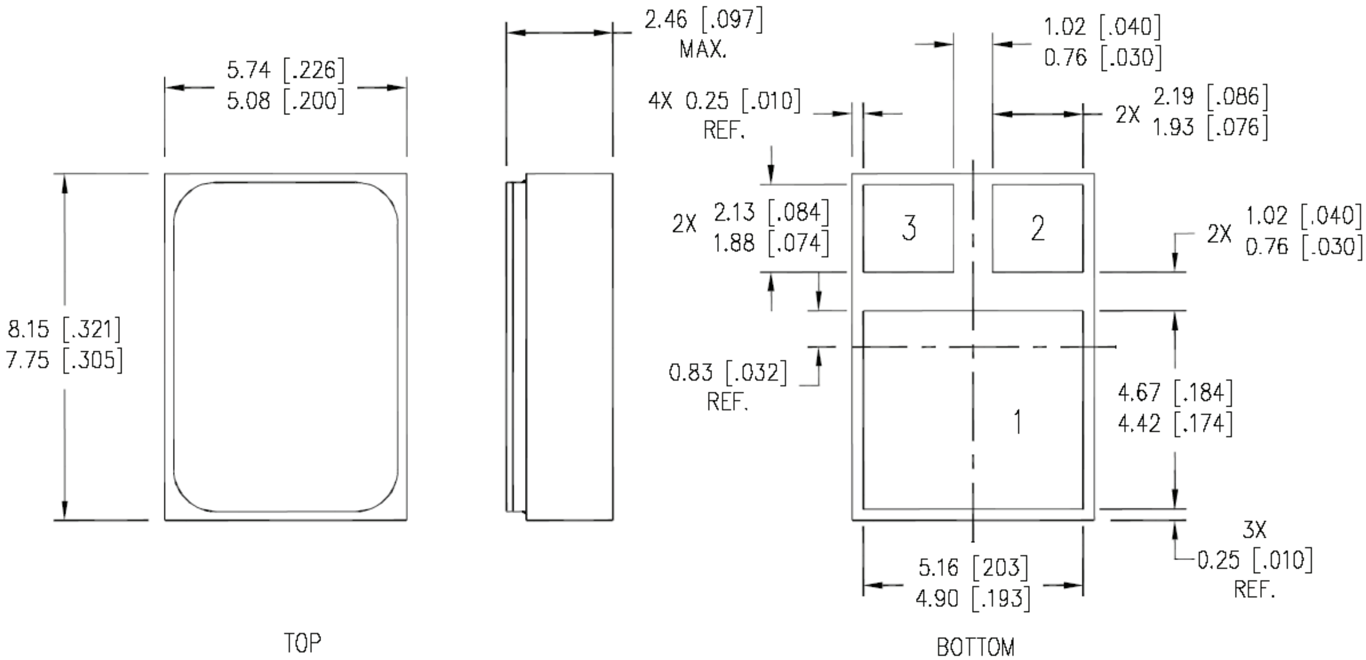


Fig 18b. Switching Time Waveforms

Case Outline and Dimensions — SMD-0.2 (Metal Lid)



NOTES:

1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

PAD ASSIGNMENT

1 = DRAIN
2 = GATE
3 = SOURCE

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